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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE ATTY. DOCKET NO. SERIAL NO. 100021-00033 Unknown APPLICANT SAITO et al

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

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EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
71	АА	4,525,836	6/85	Dayton et al	370	362	
	АВ	5,715,274	2/98	Rostoker et al	375	200	
	AC	5,872,809	2/99	Batruni	375	219	
	AD	3,775,688	11/27/73	Hinoshita et al	325_	42	
	AE	4,646,305	02/24/87	Tretter et al	371	43	
	AF	4,931,667	06/05/90	Pfennings et al	307	443	
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71	AN	10275038-A	10-13-98	Japan			xx	
	AO	EPO 375121A2	06/27/90	Europe			xx	
	АР	EPO 833342A2	04/01/98	Europe	<u> </u>		xx	
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77	AR	19744620A1	05/20/98	Germany				xx
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